CD4017B, CD4022B Types

CMOS Counter/Dividers

High-Voltage Types (20-Volt Rating)

CD4017B—Decade Counter with 10 Decoded Outputs

CD4022B—Octal Counter with 8 Decoded Outputs

The RCA-CD4017B and CD4022B are 5-stage and 4-stage Johnson counters having 10 and 8 decoded outputs, respectively. Inputs include a CLOCK, a RESET, and a CLOCK INHIBIT signal. Schmitt trigger action in the CLOCK input circuit provides pulse shaping that allows unlimited clock input pulse rise and fall times.

These counters are advanced one count at the positive clock signal transition if the CLOCK INHIBIT signal is low. Counter advancement via the clock line is inhibited when the CLOCK INHIBIT signal is high. A high RESET signal clears the counter to its zero count. Use of the Johnson counter configuration permits high-speed operation, 2-input decode-gating and spike-free decoded outputs. Anti-lock gating is provided, thus assuring proper counting sequence. The decoded outputs are normally low and go high only at their respective decoded time slot. Each decoded output remains high for one full clock cycle. A CARRY-OUT signal completes one cycle every 10 clock input cycles in the CD4017B or every 8 clock input cycles in the CD4022B and is used to ripple-clock the succeeding device in a multi-device counting chain.

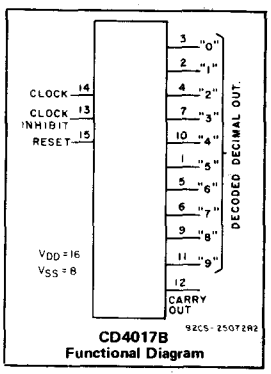
Features:

- **Fully static operation**
- **Medium-speed operation . . . 10 MHz (typ.) at V_{DD} = 10 V**
- **Standardized, symmetrical output characteristics**
- **100% tested for quiescent current at 20 V**
- **5-V, 10-V, and 15-V parametric ratings**
- **Meets all requirements of JEDEC Tentative Standard No. 13A, "Standard Specifications for Description of 'B' Series CMOS Devices"**

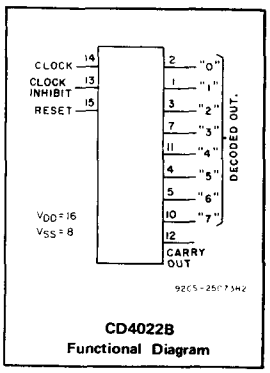
Applications:

- **Decade counter/decimal decode display (CD4017B)**
- **Binary counter/decoder**
- **Frequency division**
- **Counter control/timers**
- **Divide-by-N counting**
- **For further application information, see ICAN-6166 "COS/MOS MSI Counter and Register Design and Applications"**

The CD4017B and CD4022B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (D and F suffixes), 16-lead dual-in-line plastic package (E suffix), 16-lead ceramic flat packages (K suffix), and in chip form (H suffix).



CD4017B
Functional Diagram



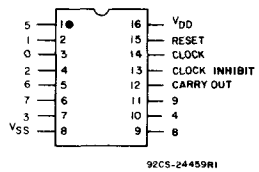
CD4022B
Functional Diagram

RECOMMENDED OPERATING CONDITIONS

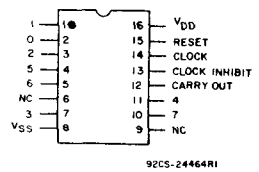
For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTICS	V_{DD} (V)	LIMITS Min.	LIMITS Max.	UNITS
Supply-Voltage Range (For T_A = Full Package-Temperature Range)		3	18	V
Clock Input Frequency, f_{CL}	5	–	2.5	MHz
	10	–	5	
	15	–	5.5	
Clock Pulse Width, t_W	5	200	–	ns
	10	90	–	
	16	60	–	
Clock Rise & Fall Time, t_{rCL}, t_{fCL}	5	UNLIMITED*		
	10			
	15			
Clock Inhibit Setup Time, t_s	5	230	–	ns
	10	100	–	
	15	70	–	
Reset Pulse Width, t_{RW}	5	260	–	ns
	10	110	–	
	15	60	–	
Reset Removal Time, t_{rem}	5	400	–	ns
	10	280	–	
	15	150	–	

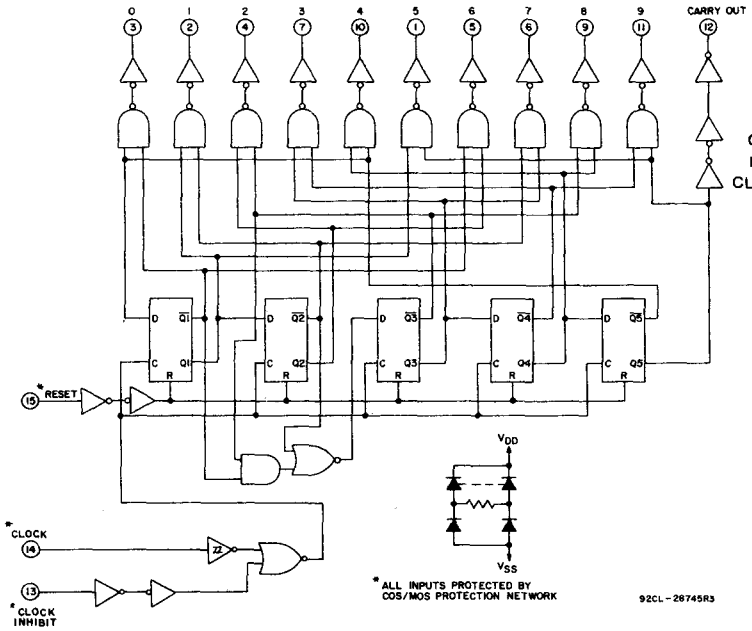
*Only if Pin 14 is used as the clock input. If Pin 13 is used as the clock input and Pin 14 is tied high (for advancing count on negative transition of the clock), rise and fall time should be ≤ 15 μs.



TOP VIEW
CD4017B
TERMINAL DIAGRAM



TOP VIEW
NC = no connection
CD4022B
TERMINAL DIAGRAM



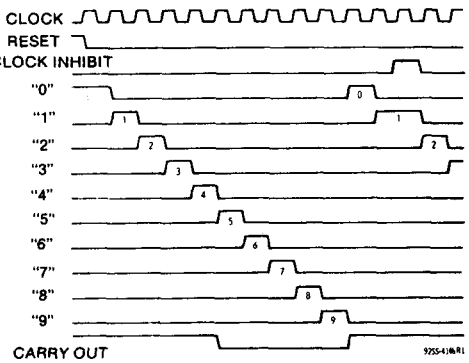


Fig. 2 – Timing diagram for CD4017B.

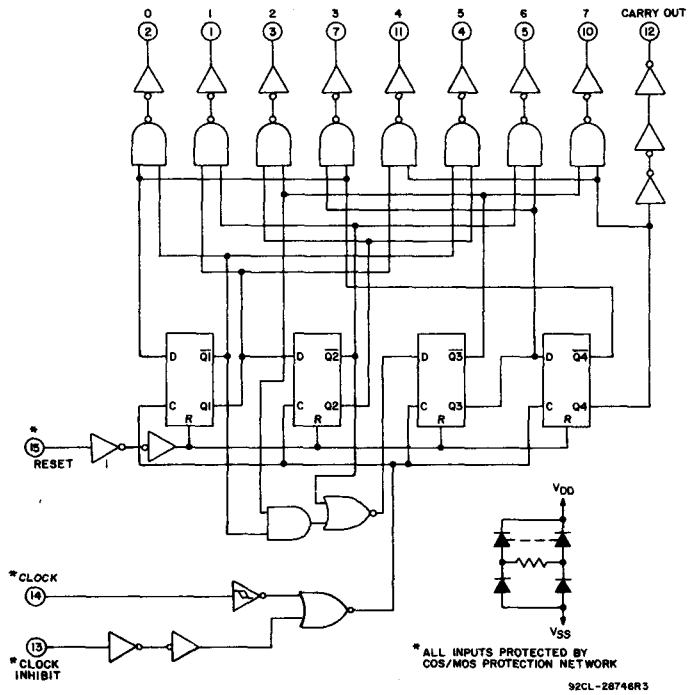


Fig. 3 – Logic diagram for CD4022B.

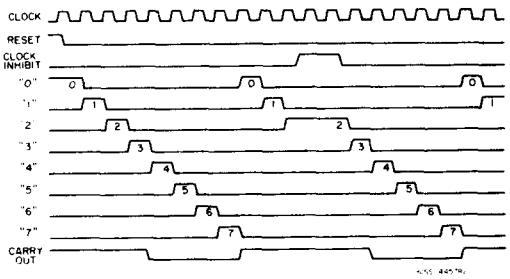


Fig. 4 – Timing diagram for CD4022B.

MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD})
(Voltages referenced to V_{SS} Terminal) ..... -0.5 to +20 V
INPUT VOLTAGE RANGE, ALL INPUTS ..... -0.5 to V_{DD} +0.5 V
DC INPUT CURRENT, ANY ONE INPUT ..... ±10 mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = -40 to +60°C (PACKAGE TYPE E) ..... 500 mW
For T_A = +60 to +85°C (PACKAGE TYPE E) ..... Derate Linearly at 12 mW/°C to 200 mW
For T_A = -55 to +100°C (PACKAGE TYPES D, F, K) ..... 500 mW
For T_A = +100 to +125°C (PACKAGE TYPES D, F, K) ..... Derate Linearly at 12 mW/°C to 200 mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR:
For T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types) ..... 100 mW
OPERATING-TEMPERATURE RANGE (T_A):
PACKAGE TYPES D, F, K, H ..... -55 to +125°C
PACKAGE TYPE E ..... -40 to +85°C
STORAGE TEMPERATURE RANGE (T_{stg}) ..... -65 to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16±1/32 inch (1.59±0.79 mm) from case for 10 s max. ..... +265°C

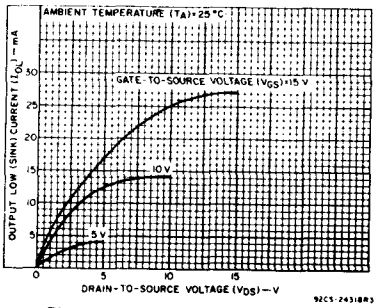


Fig. 5— Typical output low (sink) current characteristics.

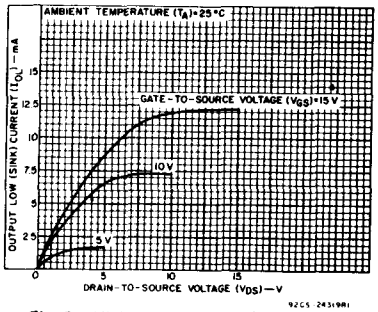


Fig. 6— Minimum output low (sink) current characteristics.

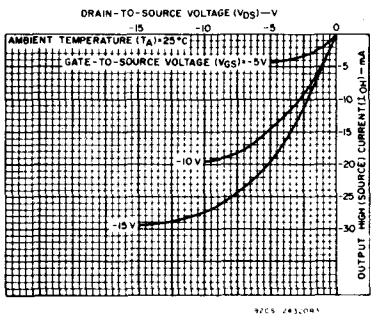


Fig. 7— Typical output high (source) current characteristics.

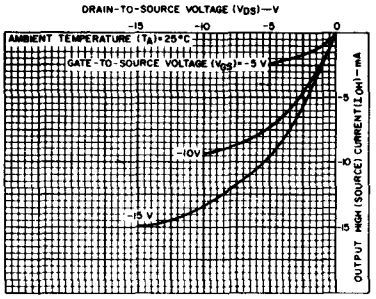


Fig. 8— Minimum output high (source) current characteristics.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C) Values at -55, +25, +125 Apply to D, F, K, H, Packages Values at -40, +25, +85 Apply to E Package							UNITS
								+25			
	V_O (V)	V_{IN} (V)	V_{DD} (V)	-55	-40	+85	+125	Min.	Typ.	Max.	
Quiescent Device Current, I_{DD} Max.	–	0,5	5	5	5	150	150	–	0.04	5	µA
	–	0,10	10	10	10	300	300	–	0.04	10	
	–	0,15	15	20	20	600	600	–	0.04	20	
	–	0,20	20	100	100	3000	3000	–	0.08	100	
Output Low (Sink) Current I_{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Output High (Source) Current, I_{OH} Min.	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	–	
	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	–	
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	–	
	13.5	0,15	15	-4.2	-4	-2.8	-2.4	-3.4	-6.8	–	
Output Voltage: Low-Level, V_{OL} Max.	–	0,5	5	0.05				–	0	0.05	V
	–	0,10	10	0.05				–	0	0.05	
	–	0,15	15	0.05				–	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	–	0,5	5	4.95				4.95	5	–	
	–	0,10	10	9.95				9.95	10	–	
	–	0,15	15	14.95				14.95	15	–	
Input Low Voltage V_{IL} Max.	0.5,4.5	–	5	1.5				–	–	1.5	V
	1,9	–	10	3				–	–	3	
	1.5,13.5	–	15	4				–	–	4	
Input High Voltage, V_{IH} Min.	0.5,4.5	–	5	3.5				3.5	–	–	
	1,9	–	10	7				7	–	–	
	1.5,13.5	–	15	11				11	–	–	
Input Current I_{IN} Max.	–	0,18	18	±0.1	±0.1	±1	±1	–	$±10^{-5}$	±0.1	µA

DYNAMIC ELECTRICAL CHARACTERISTICS

At T_A = 25°C, Input t_r, t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ

CHARACTERISTIC	CONDITIONS V_{DD} (V)	LIMITS Min.	Typ.	Max.	UNITS
CLOCKED OPERATION					
Propagation Delay Time, t_{PHL}, t_{PLH} Decode Out	5	–	325	650	ns
	10	–	135	270	
	15	–	85	170	
Carry Out	5	–	300	600	
	10	–	125	250	
	15	–	80	160	
Transition Time, t_{THL}, t_{TLH} Carry Out or Decode Out Line	5	–	100	200	ns
	10	–	50	100	
	15	–	40	80	
Maximum Clock Input Frequency, f_{CL}*	5	2.5	5	–	MHz
	10	5	10	–	
	15	5.5	11	–	
Minimum Clock Pulse Width, t_W	5	–	100	200	ns
	10	–	45	90	
	15	–	30	60	
Clock Rise or Fall Time, t_rCL, t_fCL	5, 10, 15	UNLIMITED			
Minimum Clock Inhibit to Clock Setup Time, t_s	5	–	115	230	ns
	10	–	50	100	
	15	–	35	70	
Input Capacitance, C_{IN}	Any Input	–	5	–	pF
RESET OPERATION					
Propagation Delay Time, t_{PHL}, t_{PLH} Carry Out or Decode Out Lines	5	–	265	530	ns
	10	–	115	230	
	15	–	85	170	
Minimum Reset Pulse Width, t_W	5	–	130	260	ns
	10	–	55	110	
	15	–	30	60	
Minimum Reset Removal Time	5	–	200	400	ns
	10	–	140	280	
	15	–	75	150	

* Measured with respect to carry output line.

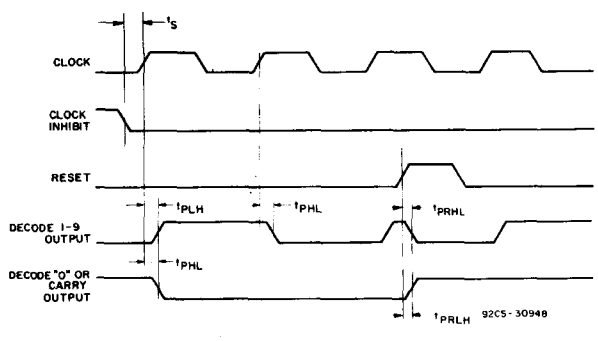


Fig. 9– Propagation delay, setup, and hold time waveforms.

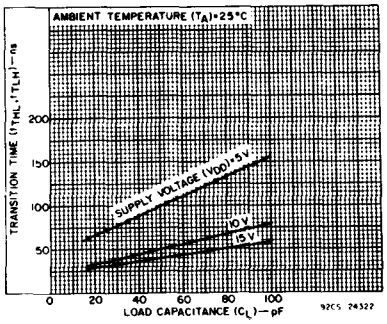


Fig. 10 – Typical transition time as a function of load capacitance.

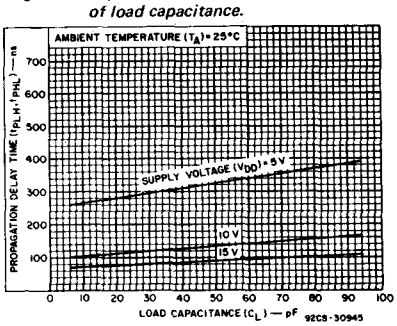


Fig. 11 – Typical propagation delay time as a function of load capacitance (clock to decode output).

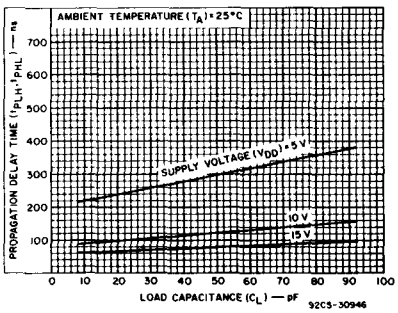


Fig. 12 – Typical propagation delay time as a function of load capacitance (clock to carry-out).

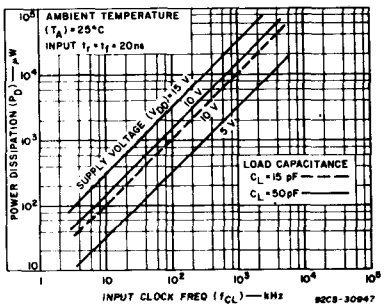


Fig. 13 – Typical dyanamic power dissipation as a function of clock input frequency.

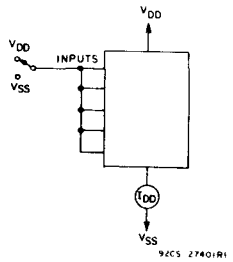


Fig. 14 – Quiescent-device-current test circuit.

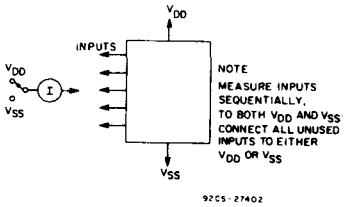


Fig. 15 – Input-leakage current.

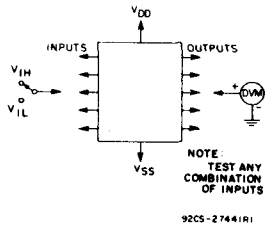


Fig. 16 – Input-voltage test circuit.

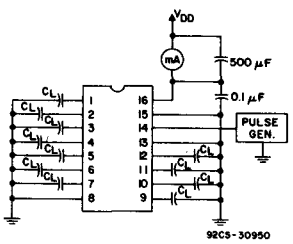


Fig. 17 – Dynamic power dissipation test circuit.

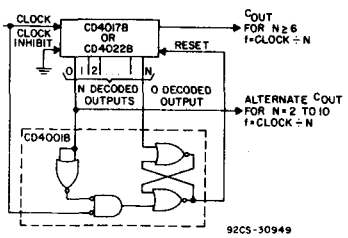
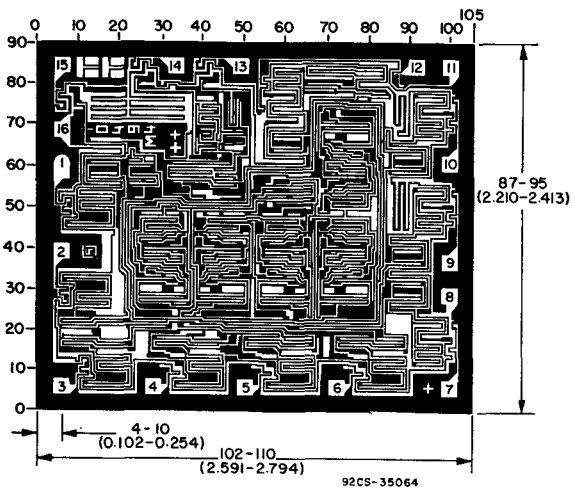
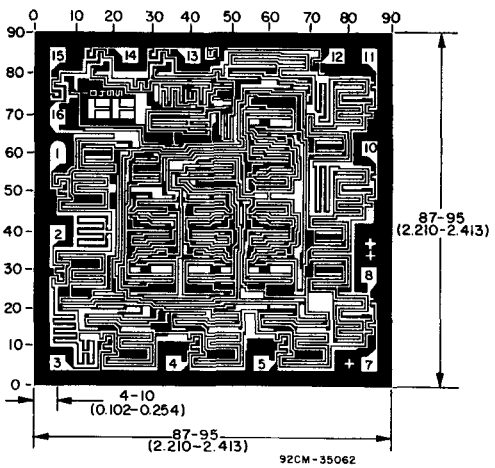


Fig. 18 – Divide by N counter ($N \leqslant 10$) with N decoded outputs.

When the N^{th} decoded output is reached (N^{th} clock pulse) the S-R flip flop (constructed from two NOR gates of the CD4001B) generates a reset pulse which clears the CD4017B or CD4022B to its zero count. At this time, if the N^{th} decoded output is greater than or equal to 6 in the CD4017B or 5 in the CD4022B, the C_{OUT} line goes high to clock the next CD4017B or CD4022B counter section. The "0" decoded output also goes high at this time. Coincidence of the clock low and decoded "0" output low resets the S-R flip flop to enable the CD4017B or CD4022B. If the N^{th} decoded output is less than 6 (CD4017B) or 5 (CD4022B), the C_{OUT} line will not go high and, therefore, cannot be used. In this case "0" decoded output may be used to perform the clocking function for the next counter.



CD4017BH



CD4022BH

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

The photographs and dimensions of each CMOS chip represent a chip when it is part of the wafer. When the wafer is separated into individual chips, the angle of cleavage may vary with respect to the chip face for different chips. The actual dimensions of the isolated chip, therefore, may differ slightly from the nominal dimensions shown. The user should consider a tolerance of −3 mils to +16 mils applicable to the nominal dimensions shown.